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- **EPIC™** (Enhanced-Performance Implanted CMOS) 1-µm Process
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and **DIP (N) Packages, Ceramic Chip Carriers** (FK), Flat (W), and DIP (J) Packages

#### description

These octal buffers and line drivers are designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

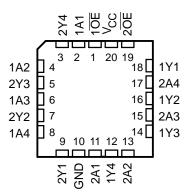
The 'AC240 are organized as two 4-bit buffers/drivers with separate output-enable ( $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes inverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

The SN54AC240 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AC240 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each buffer)							
INP	OUTPUT						
OE	Α	Y					
L	Н	L					
L	L	Н					
н	х	z					

SN54AC240 ... J OR W PACKAGE SN74AC240 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)

SN54AC240 ... FK PACKAGE (TOP VIEW)





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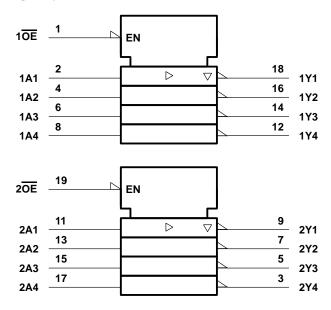
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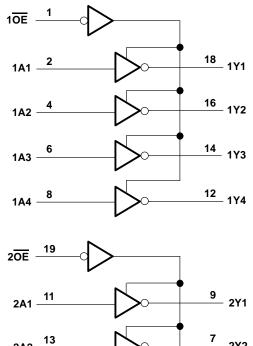
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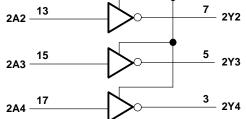
#### logic symbol<sup>†</sup>



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, $V_{CC}$ Input voltage range, $V_I$ (see Note 1) Output voltage range, $V_O$ (see Note 1) Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	$\begin{array}{ccc} -0.5 \mbox{ V to } \mbox{V}_{CC} + 0.5 \mbox{ V} \\ -0.5 \mbox{ V to } \mbox{V}_{CC} + 0.5 \mbox{ V} \\ \pm 20 \mbox{ mA} \end{array}$
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	
Continuous current through V <sub>CC</sub> or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2):	: DB package 0.6 W
	DW package 1.6 W
	N package 1.3 W
	PW package 0.7 W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.



## recommended operating conditions (see Note 3)

			SN54A	C240	SN74A	C240	UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		2	6	2	6	V
		V <sub>CC</sub> = 3 V	2.1		2.1		
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15		3.15		V
V <sub>I</sub> Input voltage		V <sub>CC</sub> = 5.5 V	3.85		3.85		
		V <sub>CC</sub> = 3 V		0.9		0.9	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V		1.35		1.35	V
		V <sub>CC</sub> = 5.5 V		1.65		1.65	
VI	Input voltage		0	VCC	0	VCC	V
VO	Output voltage		0	VCC	0	VCC	V
		$V_{CC} = 3 V$		-12		-12	
IОН	High-level output current	$V_{CC} = 4.5 V$		-24		-24	mA
		V <sub>CC</sub> = 5.5 V		-24		-24	
		$V_{CC} = 3 V$		12		12	
IOL	Low-level output current	V <sub>CC</sub> = 4.5 V		24		24	mA
		V <sub>CC</sub> = 5.5 V		24		24	
$\Delta t / \Delta v$	Input transition rise or fall rate		0	8	0	8	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DAMETED	TEST CONDITIONS	V	Т	ע = 25°C	;	SN54A	C240	SN74A	C240	UNIT
P/	RAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			3 V	2.9			2.9		2.9		
		I <sub>OH</sub> = - 50 μA	4.5 V	4.4			4.4		4.4		
			5.5 V	5.4			5.4		5.4		
Vari		I <sub>OH</sub> = – 12 mA	3 V	2.56			2.4		2.46		v
VOH			4.5 V	3.86			3.7		3.76		v
		I <sub>OL</sub> = – 24 mA	5.5 V	4.86			4.7		4.76		
		I <sub>OH</sub> = - 50 mA <sup>†</sup>	5.5 V				3.85				
		I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V						3.85		
			3 V			0.1		0.1		0.1	
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1		
			5.5 V			0.1		0.1		0.1	
M		I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	v
VOL		1	4.5 V			0.36		0.5		0.44	v
		I <sub>OL</sub> = 24 mA	5.5 V			0.36		0.5		0.44	
		I <sub>OL</sub> = 50 mA <sup>†</sup>	5.5 V					1.65			
		I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V							1.65	
1.	Data inputs	$V_{I} = V_{CC}$ or GND				±0.1		±1		±1	
tı	Control inputs	$V_{I} = V_{CC}$ or GND	<b>5.5 ∨</b>			±0.1		±1		±1	μA
loz‡		$V_O = V_{CC}$ or GND, $V_{I(OE)} = V_{IL}$ or $V_{IH}$	5.5 V			±0.25		±5		±2.5	μΑ
ICC		$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			4		80		40	μA
Ci		$V_{I} = V_{CC}$ or GND	5 V		2.5						pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

<sup>‡</sup> For I/O ports, the parameter I<sub>OZ</sub> includes the input leakage current.

switching	characteristics	over	recommended	operating	free-air	temperature	range,
V <sub>CC</sub> = 3.3 V	$\prime$ $\pm$ 0.3 V (unless o	therwis	se noted) (see Fig	jure 1)		-	•

PARAMETER	FROM	то	Т	<b>₄ = 25°C</b>	;	SN54A	C240	SN74A	C240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	А	v	1.5	6	8	1	11	1	9	
<sup>t</sup> PHL	A	T	1.5	5.5	8	1	10.5	1	8.5	ns
<sup>t</sup> PZH		v	1.5	6	10.5	1	11.5	1	11	
<sup>t</sup> PZL	OE	T	1.5	7	10	1	13	1	11	ns
<sup>t</sup> PHZ	OE	Y	1.5	7	10	1	12.5	1	10.5	
<sup>t</sup> PLZ	UE	T	1.5	7.5	10.5	1	13.5	1	11.5	ns



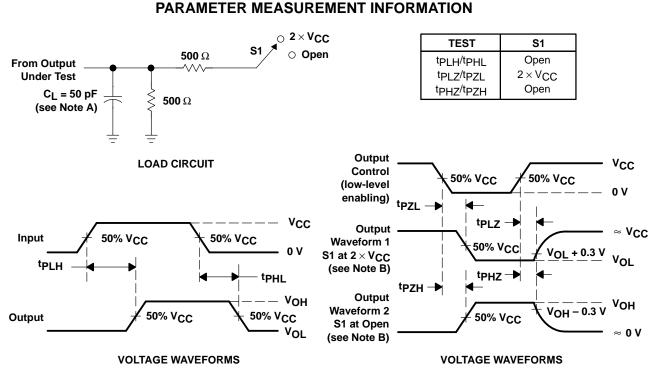
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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т	ן = 25°C	;	SN54A	C240	SN74A	C240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	А	v	1.5	4.5	6.5	1	8.5	1	7	200
<sup>t</sup> PHL	A	Т	1.5	4.5	6	1	8	1	6.5	ns
<sup>t</sup> PZH		v	1.5	5	7	1	9	1	8	-
<sup>t</sup> PZL	ŌĒ	T	1.5	5.5	8	1	10.5	1	8.5	ns
<sup>t</sup> PHZ	ŌĒ	v	2.5	6.5	9	1	10.5	1	9.5	
<sup>t</sup> PLZ	UE	ſ	2	6.5	9	1	11	1	9.5	ns

### operating characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per buffer/driver	$C_L = 50 \text{ pF},  f = 1 \text{ MHz}$	45	рF



- NOTES: A.  $C_{\mbox{L}}$  includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
  - D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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